# Integrated Front-End Electronics for SiPM Detectors in Medical Imaging Applications

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### **Outline**

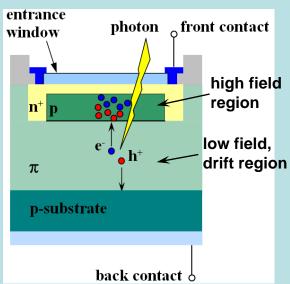
- Silicon Photo-Multipliers: a short introduction
- SiPM model and characterization
- ☐ Front-end architecture: different approaches
- Structure and design of the analog channel
- ☐ Architecture and design of multichannel ASICs: some examples and results
- Alternative architecture
- Temperature compensation of SiPM gain
- ☐ Future work

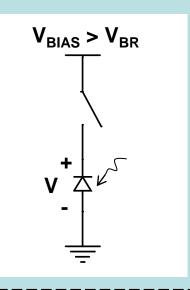


### **SPAD**

#### Single Photon Avalanche Diode, working in Geiger mode

The photodiode is reverse biased above the breakdown voltage  $V_{\text{BR}}$ 

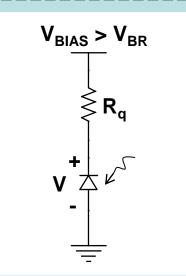




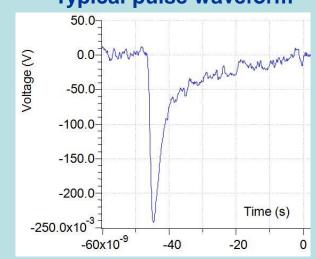
- ☐ Avalanche breakdown triggered by an absorbed photon
- No charge is extracted: the voltage across the device decreases very quickly and the avalanche is quenched when V = V<sub>BR</sub>
- ☐ The device is recharged to the bias voltage V<sub>BIAS</sub> and is ready to detect another photon
- Total charge generated:  $Q = C_{pixel} (V_{BIAS} V_{BR})$  $V_{BIAS} - V_{BR} = \Delta V = overvoltage$

### **Passive quenching**

- □ A large resistor R<sub>q</sub> is used to quench the avalanche
- □ After an avalanche, the device is recharged with a recovery time constant  $τ_R = R_α C_{\text{pixel}}$

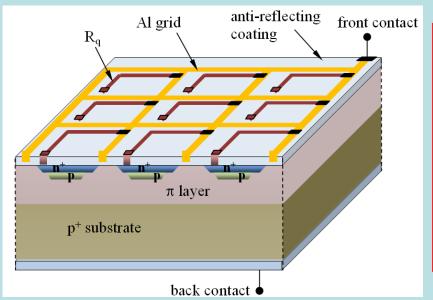


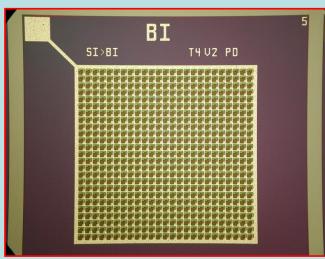
### **Typical pulse waveform**



### From SPAD to SiPM

#### Silicon Photo-Multiplier: array of N passively quenched SPAD connected in parallel





**SiPM from FBK-irst** 

Size: 1mm x 1mm

 $N = 25 \times 25$ 

Micro-cell size= 40μm x 40 μm

#### **Main features**

- ☐ Total charge proportional to the no. of incident photons
- **Photon Detection Efficiency** =  $ε_{GEOM}$  x QE x  $ε_{AVALANCHE}$
- ☐ High gain ≅ 10<sup>6</sup>
- ☐ Good timing accuracy
- Low bias voltage
- □ Compact and rugged
- ☐ Insensitive to magnetic fields
- ☐ Low cost

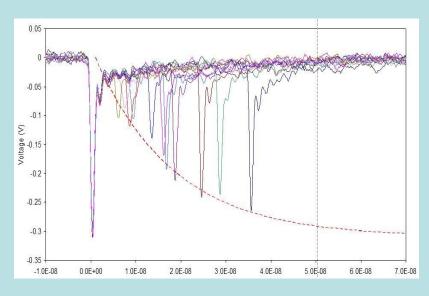
#### **Applications**

- Medical imaging (PET, SPECT, ...)
- HEP (calorimeters, scintillating fibers, ...)
- Astroparticle physics experiments
- □ Detection of low level of light (laser-range finding, photon counting, ...)

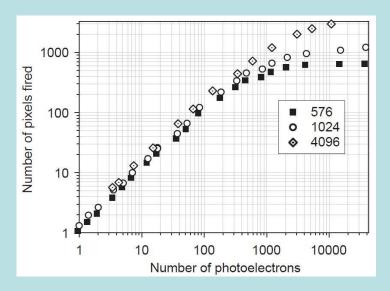


### **SiPM:** main limitations

- □ Dark count: an avalanche can be triggered by thermally generated electrons
- Optical cross-talk: a photon can be emitted by a micro-cell undergoing avalanche breakdown and can trigger another avalanche in an adjacent micro-cell
- Afterpulsing: the avalanche can be retriggered in a micro-cell during the recovery phase, due to the release of carriers trapped in deep energy levels
- ☐ Gain drift with the temperature
- □ Saturation: the probability that one micro-cell is hit by more than one photon becomes significant

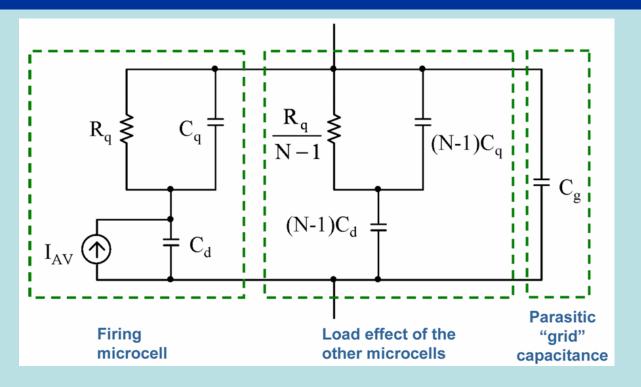






**Saturation** (V. Andreev et al., NIMA 540, pp. 368-380 (2005)

### SiPM model



 $R_q$ : quenching resistor (hundreds of  $k\Omega$ )

C<sub>d</sub>: photodiode capacitance (few tens of fF)

C<sub>q</sub>: parasitic capacitance (smaller than C<sub>d</sub>)

I<sub>AV</sub>: short current pulse containing the charge Q delivered by a single micro-cell during the avalanche

C<sub>g</sub>: parasitic capacitance due to the routing of the bias voltage to the N microcells, realized with a metal grid.

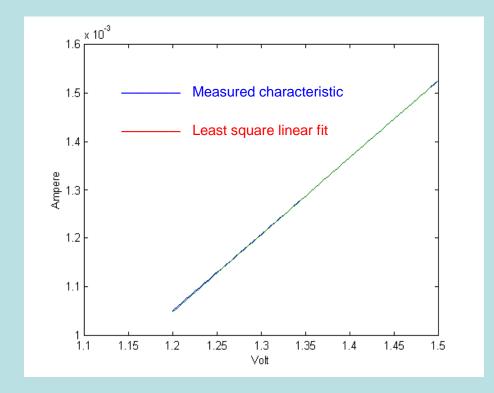
**Example:** metal-substrate unit area capacitance 0.03 fF/mm<sup>2</sup> metal grid = 35% of the total detector area = 1mm<sup>2</sup>



**Cg** ≅ 10pF, without considering the fringe parasitics

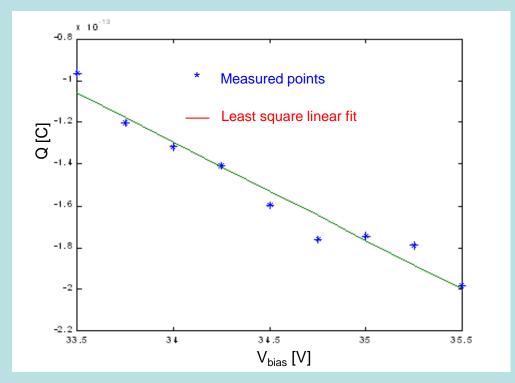
### Parameter extraction I

 $R_q$ : forward characteristic of the SiPM (slope almost constant and equal to  $R_q/N$ )



Forward characteristic of a SiPM manufactured by FBK-Irst.

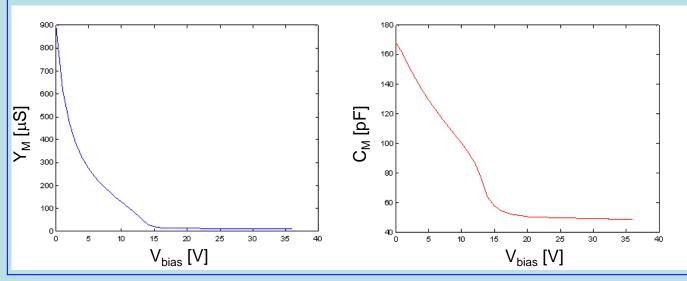
 $(C_d+C_q)$  and  $V_{BR}$ : charge associated to a single dark pulse as a function of the bias voltage  $Q=(C_d+C_q)(V_{BIAS}-V_{BR})$ 



Charge contained in a single dark count pulse vs. bias voltage

### Parameter extraction II

- ☐ CV plotter measurements of the SiPM near the breakdown voltage: Y<sub>M</sub> and C<sub>M</sub>
- $\square$  According to the SiPM model,  $Y_M$  and  $C_M$  are expressed in terms of  $C_{dtot} = NC_d$ ,  $C_{qtot} = NC_q$ ,  $R_{qtot} = R_q/N$  and the frequency  $\omega$  of the signal used by the CV plotter.



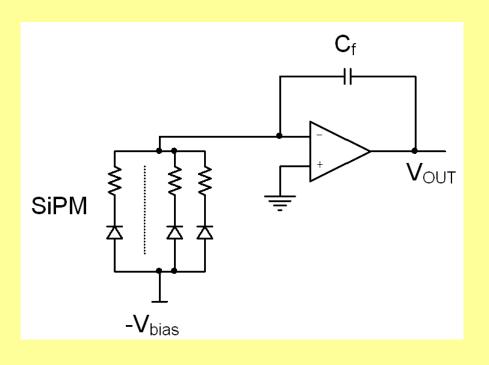
CV plotter measurement results for a SiPM manufactured from FBK-Irst.

$$Y_{M}$$
  $C_{M}$   $C_{g}$   $C_{g}$ 

$$Y_{M} = \frac{\omega^{2} R_{qtot} C_{dtot}^{2}}{1 + \omega^{2} R_{qtot}^{2} C_{t}^{2}} \cong \omega^{2} R_{qtot} C_{dtot}^{2} \qquad \left(C_{t} = C_{dtot} + C_{qtot}\right) \longrightarrow C_{d}, C_{q}$$

$$C_{M} = \frac{C_{dtot} + C_{g} + \omega^{2} R_{qtot}^{2} C_{t} (C_{g} C_{t} + C_{qtot} C_{dtot})}{1 + \omega^{2} R_{qtot}^{2} C_{t}^{2}} \cong C_{dtot} + C_{g} \qquad C_{g}$$

# Front-end electronics: different approaches I



#### **Charge Sensitive Amplifier**

The charge delivered by the detector is collected on C<sub>f</sub>

#### Example:

Maximum  $\Delta V_{OUT}$ : 3V

SiPM gain: 10<sup>6</sup>

No of hit microcells: 300

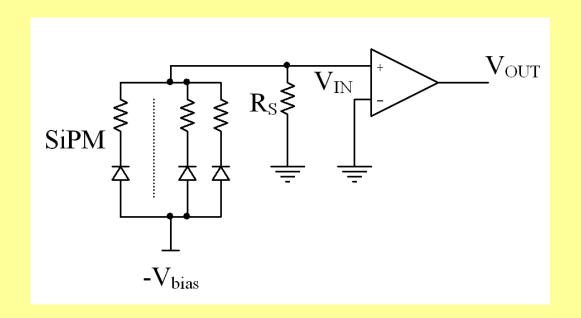
Total charge Q<sub>TOT</sub>: 48pC

Large integration capacitance needed:  $C_f = 16pF$ 

- Dynamic range problems
- Large silicon area required
- ☐ Large capacitive loads: power consumption issues or bandwidth limitations



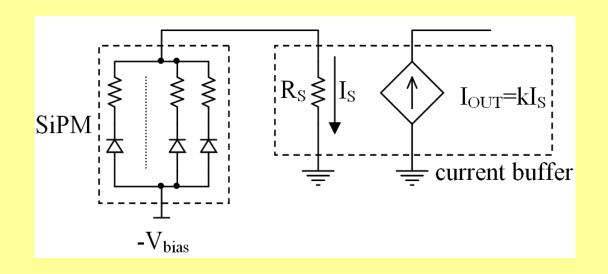
### Front-end electronics: different approaches II



Voltage Amplifier

- A current-to-voltage conversion of the SiPM signal is realized by means of R<sub>S</sub>
- Often used for characterization purposes
- V<sub>OUT</sub> must be integrated to extract the charge information: further V-I conversion needed.
- □ No virtual ground at the amplifier input: R<sub>s</sub> must be small to preserve linearity
- ☐ Small R<sub>s</sub>: large gain, wide-bandwidth voltage amplifier required (power consumption issues)

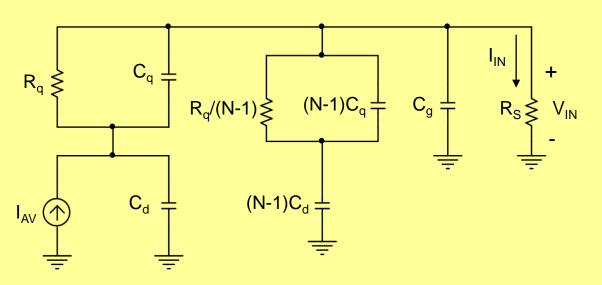
# Front-end electronics: different approaches III



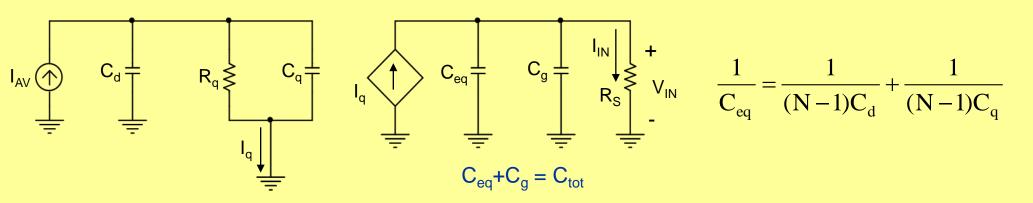
**Current Amplifier** 

- R<sub>S</sub> is the very small input impedance of the current amplifier
- ☐ The output current can be easily replicated (e.g. by means of current mirrors) and further processed (e.g. integrated)
- ☐ The circuit is inherently fast (low impedance nodes)
- Less problems of dynamic range, also for decreasing supply voltages

# SiPM coupled to the front-end



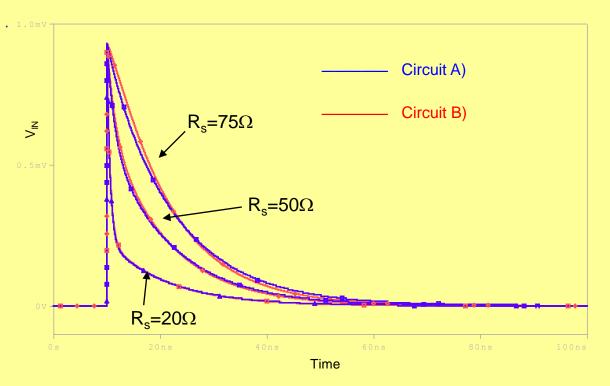
A) SiPM coupled to an amplifier with input impedance R<sub>s</sub>



B) Simplified circuit  $(R_S \ll R_q/N)$ 



### SiPM + front-end behaviour



Response of the circuits A) and B) to a single dark pulse (160fC) for three different values of Rs and typical parameter values

$$\begin{split} V_{IN}(t) &\cong \frac{QR_S}{\tau_r - \tau_{IN}} \left( \frac{\tau_q - \tau_{IN}}{\tau_{IN}} exp(-\frac{t}{\tau_{IN}}) + \frac{\tau_r - \tau_q}{\tau_r} exp(-\frac{t}{\tau_r}) \right) \\ & \left( \tau_q = R_q C_q \right) \end{split}$$

Simplified circuit: two time constants

• 
$$\tau_{IN} = R_s (C_{eq} + C_g) = R_s C_{tot}$$

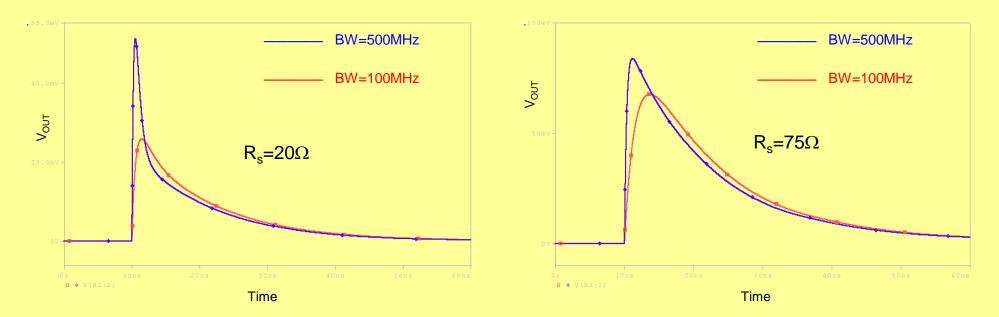
• 
$$\tau_r = R_q(C_d + C_q)$$

The peak of  $V_{\rm IN}$  is almost independent of  $R_{\rm s}$ 

A fraction  $Q_{IN}$  of the charge Q delivered during the avalanche is almost instantly collected on  $C_{tot}$ 

$$V_{INMAX} \cong \frac{Q_{IN}}{C_{tot}}$$
  $Q_{IN} = Q \frac{C_q}{C_d + C_q}$ 

# Bandwidth of the amplifier

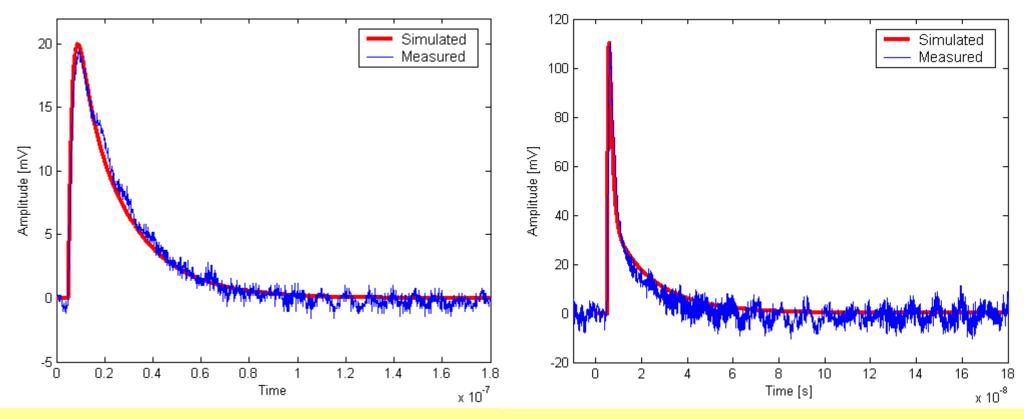


Amplifier output voltage for a single dark pulse: same gain and different bandwidth

- The bandwidth of the amplifier directly affects the **rise time** of the waveform
- The peak of the waveform is strongly dependent on the amplifier bandwidth, especially for low values of Rs
- The time needed to collect the charge is also slightly influenced by the amplifier bandwidth
- The same conclusions are valid also for the waveform of the output current obtained with a current amplifier

### **Model validation**

Two different amplifiers have been used to read-out the same SiPM (FBK-Irst N = 625, micro-cell size  $40x40\mu m^2$ )

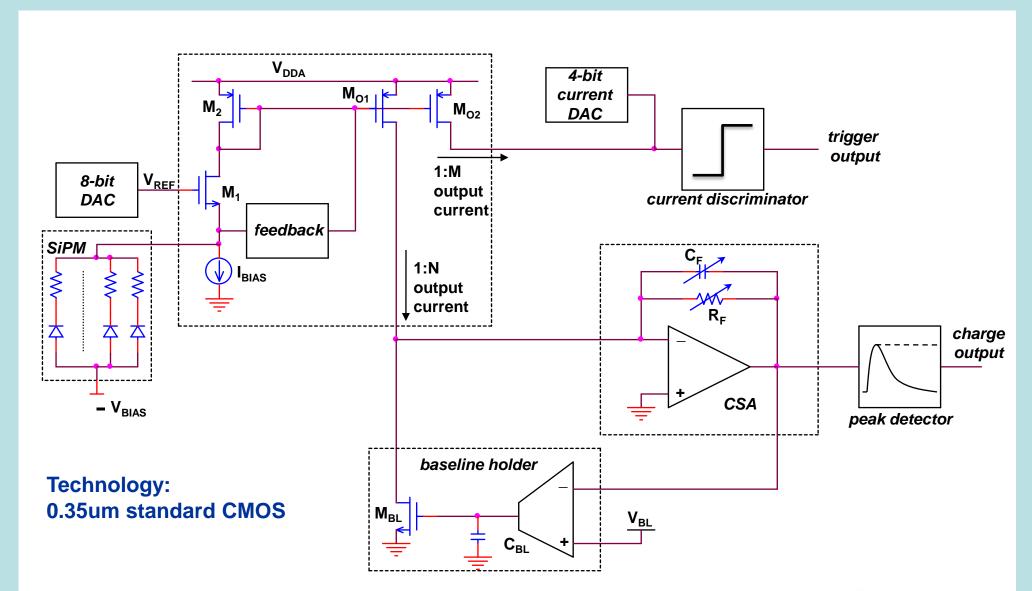


Transimpedance amplifier (discrete BJTs)
 BW=80MHz Rs=110Ω Gain=2.7kΩ

- b) Voltage amplifier (hybrid RF circuit)BW=360MHz Rs=50Ω Gain=140
- The model extracted according to the procedure described above has been used in the SPICE simulations
- · The fitting between simulations and measurements is quite good



# Structure of the analog channel



# Main features and parameters of the analog channel

#### **Current buffer**

- ☐ Small signal bandwidth: 250MHz
  - (with a 30pF detector)
- $\Box$  Low input resistance: 17 $\Omega$
- ☐ Scaling factors: N=10, M=20
- $\Box$   $V_{REF}$  variable in the range 1V÷2V
- Total current consumption: 800μA

#### Fast Current Discriminator

- Leading edge
- ☐ Trise ≈ 300ps
- ☐ Threshold programmable :
  - 4-bit current DAC from 0 to 40μA

#### CSA

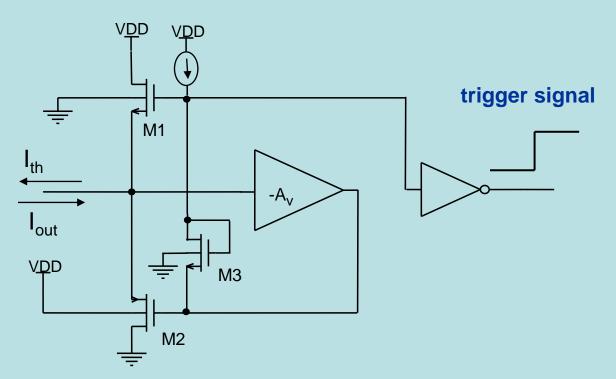
- □ Continuous passive reset
- **□** Variable gain: C<sub>F</sub>=1pF, 2pF, 3pF
- □ Damping time constant: 200ns
- **☐** Output voltage range: 0.3V ÷ 2.7V

#### Baseline holder

- □ Very slow feedback loop
- □ "Ad hoc" techniques to reproduce large time constants
- Small baseline shifts at high event rates (-1mV @ 100kHz, full dynamic range)



### The current discriminator



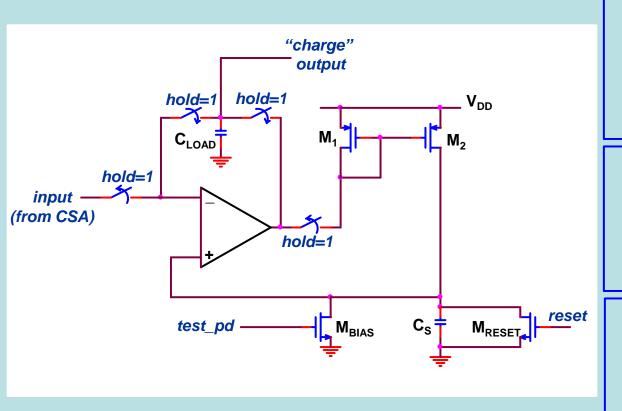
#### Principle of operation

If  $I_{out}$  is less than  $I_{th}$ , then  $M_1$  is on and  $M_2$  is off. When  $I_{out}$  becomes greater than  $I_{ref}$ , the MOSFETs switch and the amplifier output goes low, thus the inverter output goes high



### Peak detector modes of operation

Logic control signals involved: "hold" and "test\_pd"



test\_pd=1, hold=0: voltage follower

The voltage on  $C_S$  follows the CSA output , thanks to the current of  $M_{\text{BIAS}}$ 

test\_pd=0, hold=0: peak detector

The voltage on  $C_S$  tracks the peak of the CSA output ( $M_{BIAS}$  is OFF)

test\_pd=0, hold=1: buffer

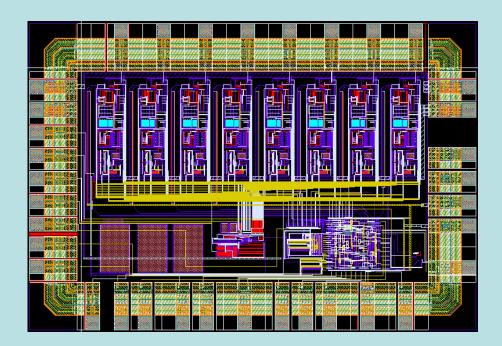
The voltage stored on C<sub>S</sub> is buffered ad transferred to the output of the circuit.



### Multichannel ASICs available

#### **BASIC8**

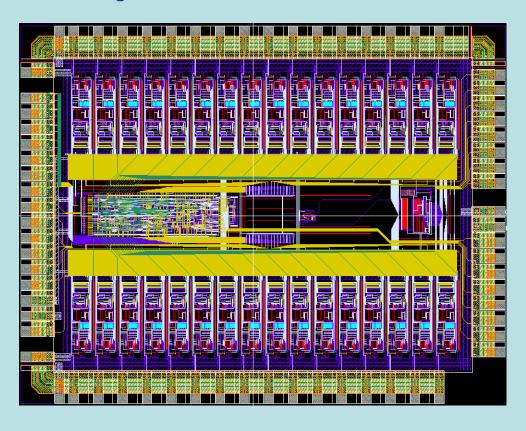
- 8 channels
- ☐ "Sparse" and "serial" read-out modes
- 8 bit SAR integrated ADC



Layout of BASIC8 (3.2 x 2.2 mm<sup>2</sup>)

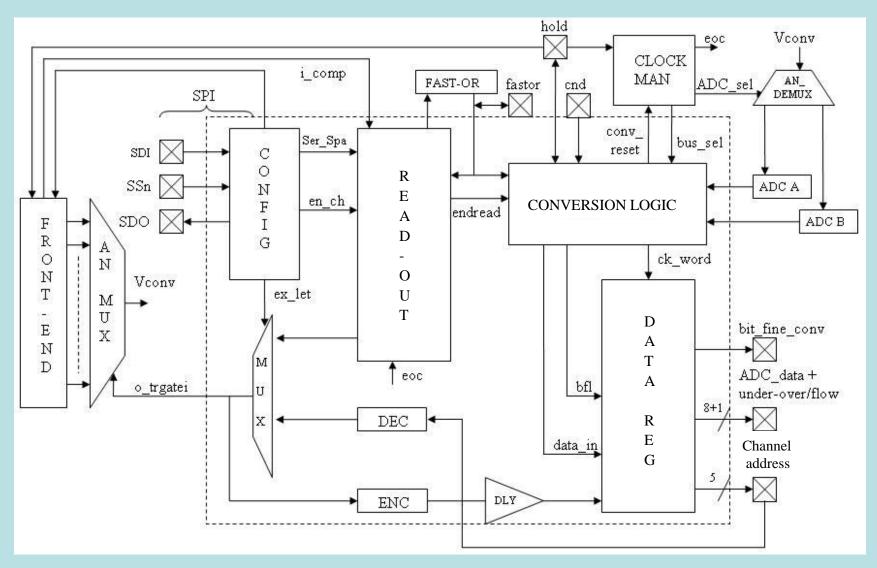
#### BASIC32

- ☐ 32 channels
- ☐ Enhanced programmability and RO modes
- No integrated ADC



Layout of BASIC32 (5 x 3.9 mm<sup>2</sup>)

# BASIC32: block diagram



### **BASIC32:** main features

### **Acquisition modes**

#### **Internal read-out**

Internal trigger ("fast-OR") Sparse Serial

#### External read-out

External control of the PD's External channel addressing

Multiplexing, PD control and reset of the channels managed by the read-out logic

#### **Configuration logic**

- ☐ SPI interface
- ☐ 56-bit configuration word
- Verification features

#### **Read-out logic**

- Multiplexer management
- □ Fast-or management
- Masking and reset of the channels

#### **Conversion logic**

- ADC management
- □ Data flow management

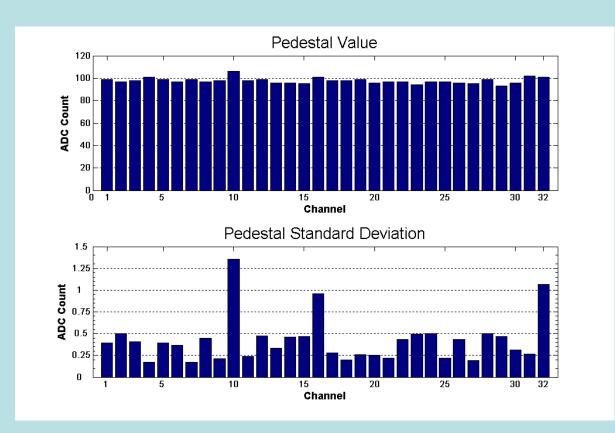
#### **Coincidence management**

☐ External "coincidence" signal:

In internal read-out mode, the

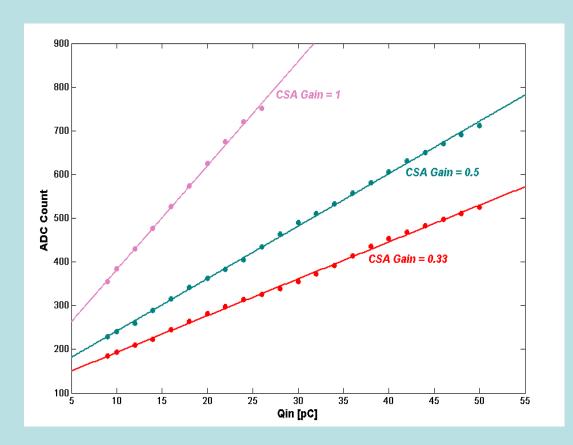
acquisition is conditioned by this signal

# **Experimental results: pedestals**



- □ Acquisition mode: internal read-out, external trigger, serial
- ☐ The "test\_pd" signal of the PD's is controlled externally, to avoid the discharge of the Cs capacitance during the "hold=1" phase
- ☐ An ADC count corresponds to about 3.9 mV
- ☐ Pedestals quite uniform
- □ Some channels exhibit more noise than the average, i.e. about 1.7mV rms, corresponding to 50fC rms

# Experimental results: injection capacitance, gain



Charge to voltage gain of the analog channel

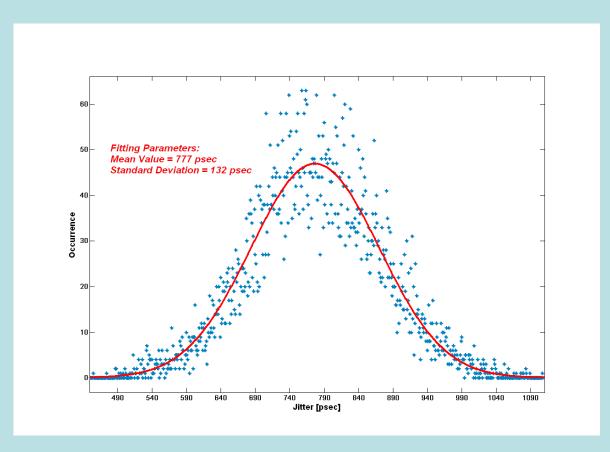
$$\frac{\Delta V_{OUT}}{Q_{in}} = \frac{1}{NC_F}$$

$C_{F}$	1pF	2pF	3pF
EXPECTED GAIN	100	50	33
MEASURED GAIN	94	47	33

Expected and measured values of the gain  $\Delta V_{OUT}/Q_{in}$  [mV/pC]

- $\square$  Overall charge to voltage gain very close to the expected one (max. deviation  $\cong$  6%)
- □ Max dynamic range  $\cong$  70pC @  $C_F$ =3pF (1% linearity error)

# Experimental results: injection capacitance, timing



Timing accuracy of the fast-OR response vs the input pulse

- ☐ Measured standard deviation  $\sigma_{meas} \cong 130 \text{ ps}$
- Intrinsic error of the measurement setup

$$\sigma_{\mathsf{setup}} \cong 60 \; \mathsf{ps}$$

☐ Resulting intrinsic timing accuracy of the fast-OR signal

$$\sigma_{int} \cong 115 \text{ ps}$$

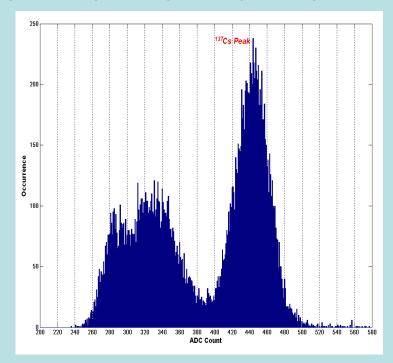
# Experimental results: coupling to SiPM+scintillator (I)

- □ SiPMs from Hamamatsu a) 3600 micro-cells,  $3x3mm^2$ , (gain =  $7.5x10^5$  @  $V_{BIAS}$ =71.3V)
  - b) 782 micro-cells,  $3.22x1.19mm^2$ ,  $(gain = 1.3x10^5 @ V_{BIAS} = 71.2V)$
- SiPMs coupled to a small LYSO scintillator 3x3x10mm³
- ☐ The SiPM+LYSO detector has been coupled to a channel of the ASIC and exposed to different radiation sources:

<sup>176</sup>Lu (203keV and 307keV), <sup>22</sup>Na (511keV), <sup>137</sup>Cs (662keV), <sup>57</sup>Co (122keV)



Hamamatsu SiPM coupled to the LYSO crystal

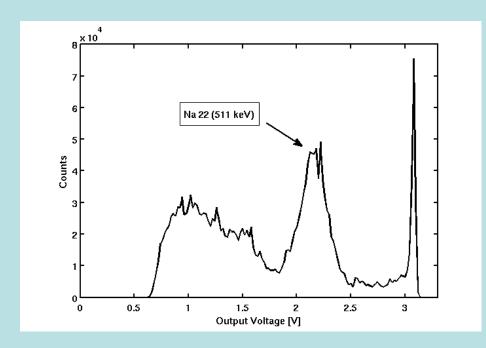


Example of <sup>137</sup>Cs spectrum (≅ 12% FWHM)

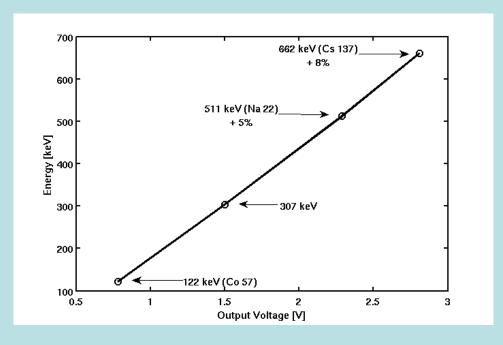
- ☐ 3x3mm<sup>2</sup> SiPM
- $\Box$  Gain = 33mV/pC

# Experimental results: coupling to SiPM+scintillator (II)

□ 782 micro-cells Hamamatsu SiPM,  $V_{BIAS}$  = 70V, gain = 0.33mV/pC



Spectrum of <sup>22</sup>Na (about 22% FWHM)



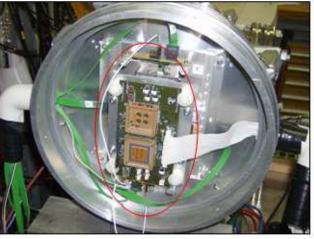
Energy vs average output voltage for the different sources

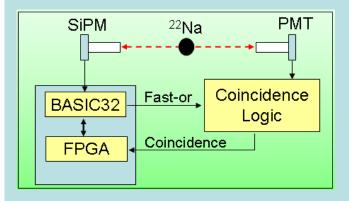
Corrections applied to compensate for SiPM saturation (large no. of fired micro-cells)

# Measurements of SiPM in coincidence with a PMT (I)

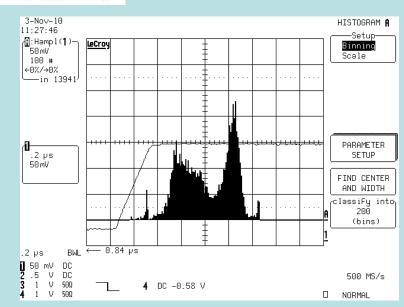
Measurement setup at CERN (courtesy of E. Chesi, A. Rudge and J. Seguinot)



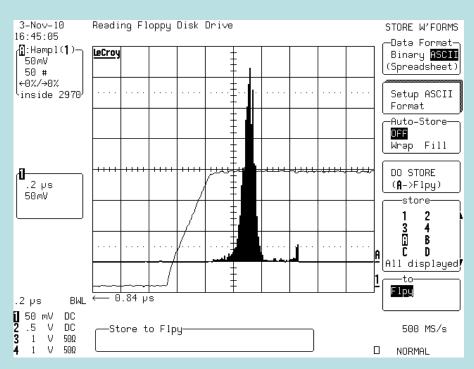




- Measurements taken in coincidence with a PMT
- Very low event rate (≅ 1.9 Hz)
- Signals acquired with an oscilloscope
- □ Spectrum of <sup>22</sup>Na spectrum very similar to the one shown in the previous slide (low threshold)

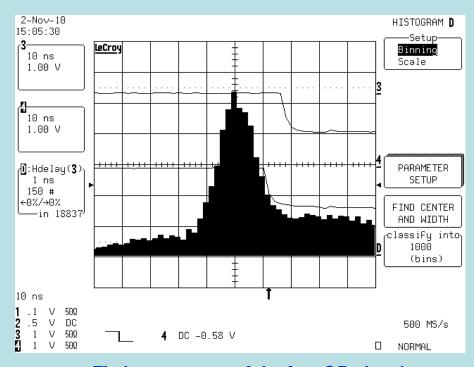


# Measurements of SiPM in coincidence with a PMT (II)



Energy spectrum of <sup>22</sup>Na

 □ Threshold increased to get rid of the Comptons:
 energy resolution ≅ 11% FWHM



Timing accuracy of the fast-OR signal vs the trigger provided by the PMT

Low threshold level: timing accuracy ≅ 1.2 ns FWHM



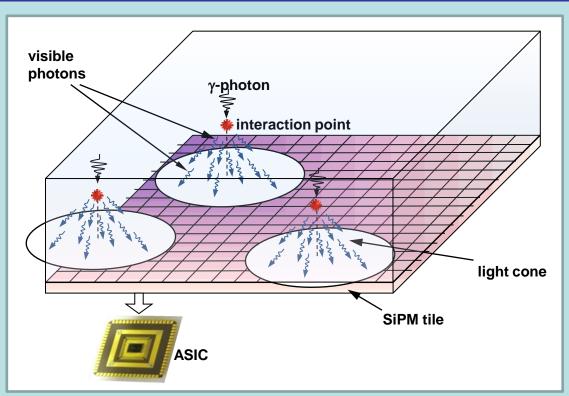
### A different architecture: motivations

#### Application: continuous scintillator slab

The Depth Of Interaction information can be related to the asymmetry of the cluster of SiPM found over threshold on the two sides of the scintillator

SiPMs at the border of the cluster receive a small total number of photons, distributed in time according to the time constant of the scintillator

The current signal can be under the threshold set on the current level, thus they would be ignored in a sparse read-out acquisition

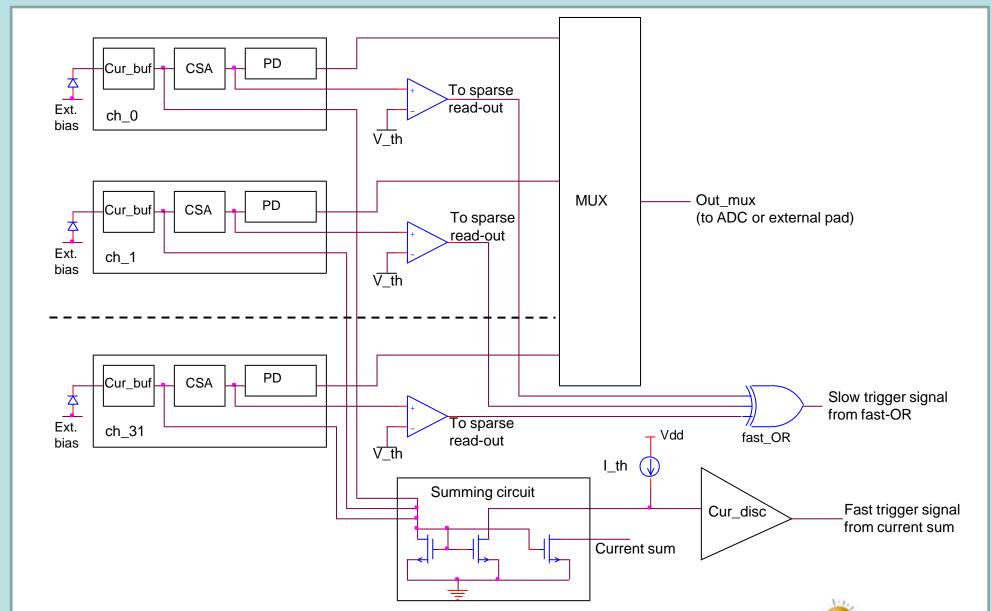


#### **Proposed solution**

- 1) Sum of the current pulses from all the channels (exploiting the "fast" signal path of the FE)
- 2) Current discriminator which fires when the **sum** of the currents overcomes the threshold
- 3) Voltage discriminator at the "**charge**" output of each channel ("slow" signal path), instead of the current discriminator in the "fast" signal path, to make effective the sparse read-out operation

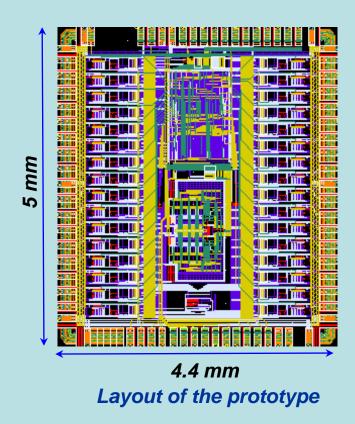


# **New proposed architecture**



## Last version of the ASIC: BASIC32\_ADC

- Internal 8-bit subranging ADC
- Extended dynamic range (more than 100pC)
- ☐ Improved configuration flexibility (524 bits) (channels configurable independently)
- Analog current sum output
- ☐ Analog multiplicity output
- ☐ The internal read-out procedure can be started by the "slow" (fast-OR of the voltage comparators) or "fast" (current discriminator) trigger
- Currently in test phase



# SiPM gain: temperature dependence

$$G=Q/e=[C_{pixel} (V_{BIAS}-V_{BR})]/e$$

SiPM gain

**C**<sub>pixel</sub>= total capacitance of the single micro-cell

**V<sub>BIAS</sub>= detector bias voltage** 

**V**<sub>BR</sub>= breakdown voltage

□ Breakdown voltage temperature dependance:

$$V_{BR}(T)=V_{BR0}[1+\beta(T-T_0)]$$

β order of magnitude: 10<sup>-3</sup> /°C

**□** Gain temperature dependance:

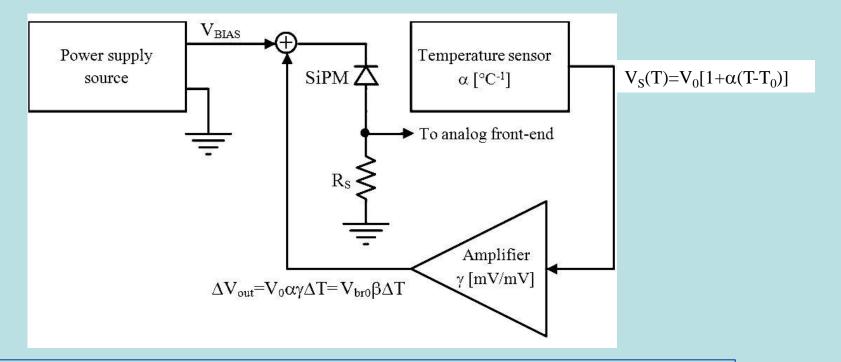
$$\frac{\text{dG}}{\text{dT}} = -\frac{\textbf{C}_{\text{pixel}}}{\textbf{e}} \, \textbf{V}_{\text{BR}\,0} \boldsymbol{\beta}$$

better than APD, but still a problem to be addressed

### Solutions proposed in the literature

#### **Based on open loop techniques:**

- a. Measurement of parameter β
- b. Measurement of the temperature (using a sensor)
- c. SiPM bias voltage adjustment  $\Delta V_{BIAS} = \Delta V_{BR}(T)$



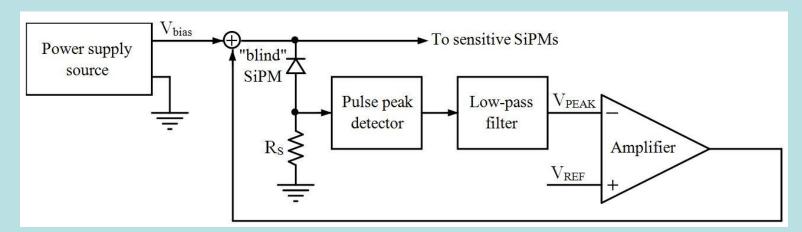
Parameters  $\beta$ ,  $\alpha$  and  $\gamma$  must be known and/or controlled with good accuracy



# **New proposed solution**

#### **Closed loop technique:**

- a. A SiPM not exposed to incident photons ("blind" SiPM) is used as a temperature sensor
- b. Measurement of the average dark pulse amplitude  $V_{PEAK}$  of the blind SiPM (proportional to the gain)
- c. Blind SiPM bias voltage automatically adjusted by a feedback loop to make  $V_{PEAK}$  (thus the gain) constant and equal to a reference value  $V_{REF}$

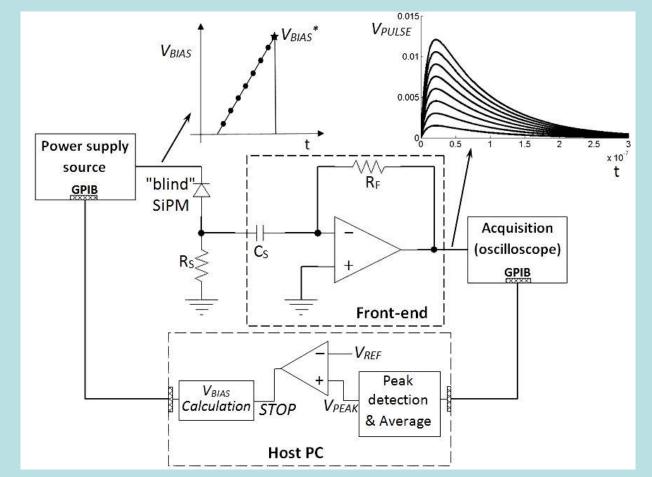


Main requirement: same  $\beta$  for the blind SiPM and the active detectors



### **Experimental proof of principle**

- a. Single measurement cycle:  $V_{BIAS}$  increased linearly on the bind SiPM until the desired  $V_{PEAK}$  (i.e. the required gain) is reached ( $V_{BIAS} = V_{BIAS}^*$ )
- b. Measurement cycles continuously applied :  $V_{BIAS}^*$  tracks the temperature variations and is applied to the active SiPMs

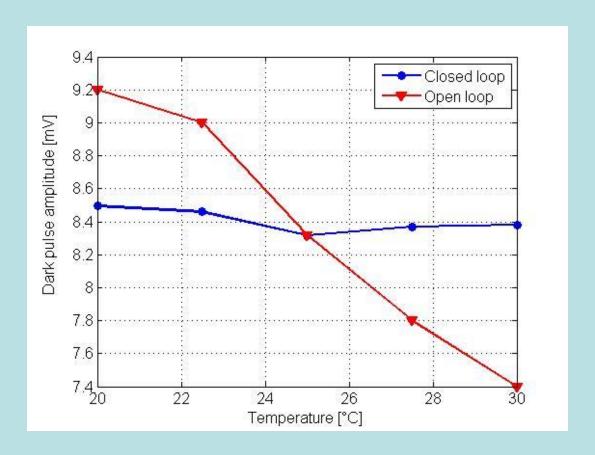




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### First results

- □ Two SiPMs from FBK-irst, 400 micro-cells, 50x50 μm² used as blind and sensitive detectors
- Temperature controlled by means of a small Peltier cell



- $\Box$  Open loop variation of the gain  $\cong$  20%
- $\Box$  Closed loop variation of the gain  $\cong$  2%

# Work in progress

- Application of BASIC in a PET prototype: small animal PET (Pisa)
- ☐ Characterization of the last version of BASIC with modified architecture
- ☐ Effective circuit implementation of the temperature compensation technique
- □ Statistical modelling of the current pulse waveform produced by the system scintillator + SiPM + FE electronics for timing accuracy evaluation
- Design of a new SiGe ASIC with enhanced timing capabilities

